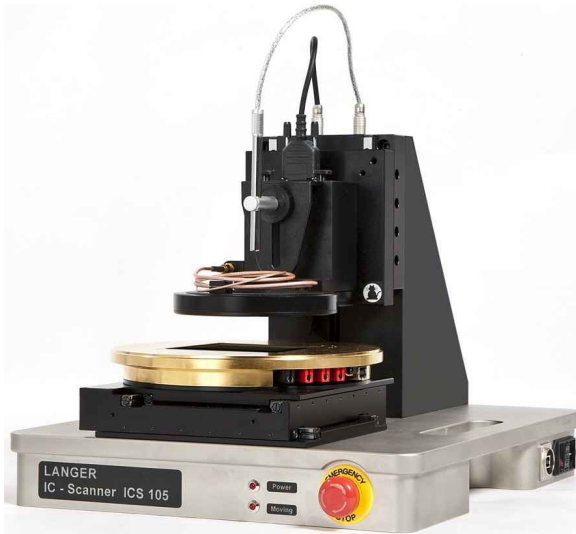


ICS 105 set

IC Scanner 4-Axis Positioning System



Short description

The ICS 105 IC scanner allows for measurements of high-frequency near fields above ICs. Depending on the used ICR near-field microprobe magnetic or electric fields can be measured with a measuring resolution of 50 to 100 μm . The probe can also be automatically rotated to determine the magnetic field's direction.

Optionally the ICS 105 scanner can be used for measurements above small assemblies in combination with UH-DUT universal holder and SH 01 probe holder.

The IC scanner can be set up for ESD or EFT immunity tests on ICs in a few simple steps.

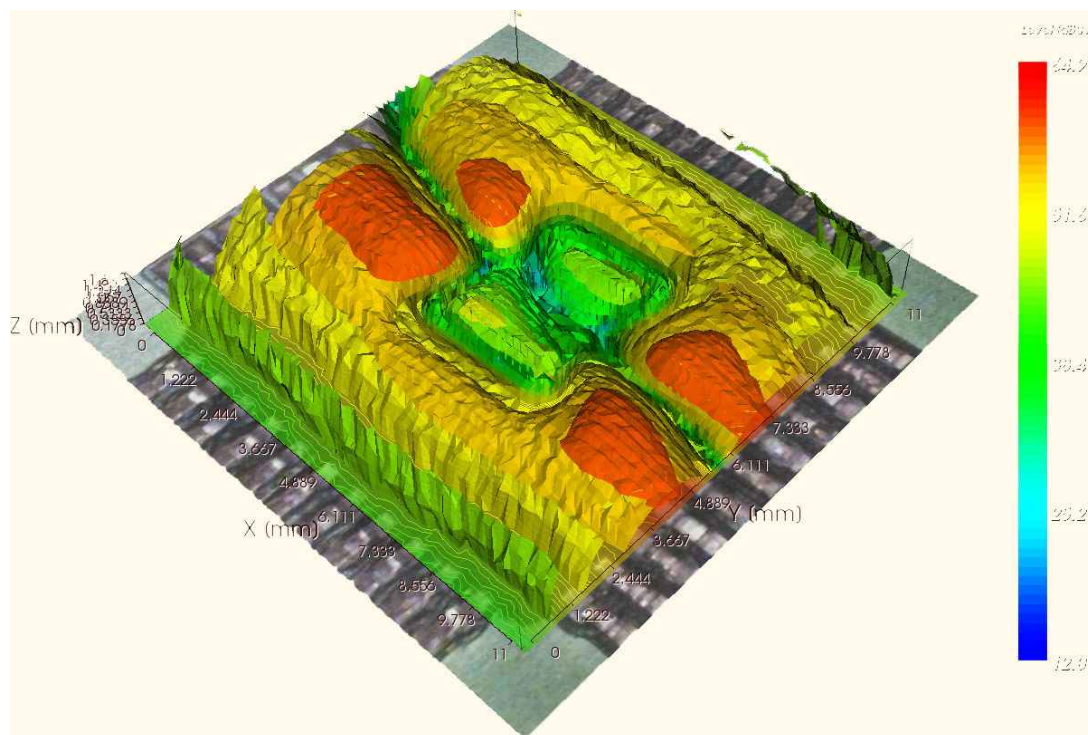
Scope of delivery

- 1x ICS 105, 4-Axis Positioning System
- 1x CS-Scanner, ChipScan-Scanner Software / USB
- 1x GND 25, Ground Plane
- 1x UH DUT set, Universal Holder for Langer scanner
- 1x DM-CAM, Digital Microscope Camera
- 1x SH 01, Probe Holder for Langer scanner
- 1x ICS Flight case, ICS Flight Case
- 1x ICS 105 m, ICS 105 User Manual

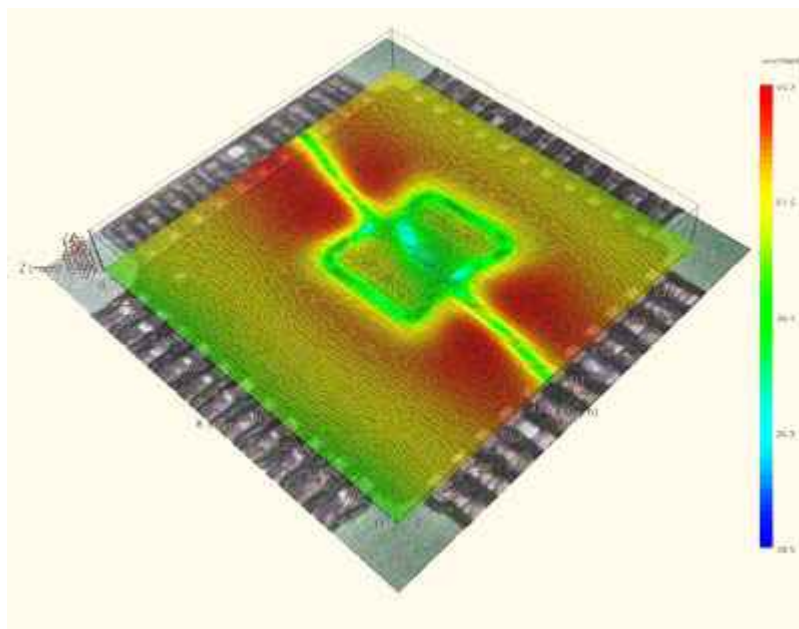
Technical parameters

Supply voltage	110 / 230 V
Interface	USB
Max. traverse range	(50 x 50 x 50) mm; α -Rotation $\pm 180^\circ$
Min. step size	(10 x 10 x 10) μm ; α -Rotation 1°
Positioning speed	(10 x 10 x 5) mm/s; α -Rotation 90°/s
Weight	23 kg
Sizes (L x W x H)	(350 x 400 x 420) mm

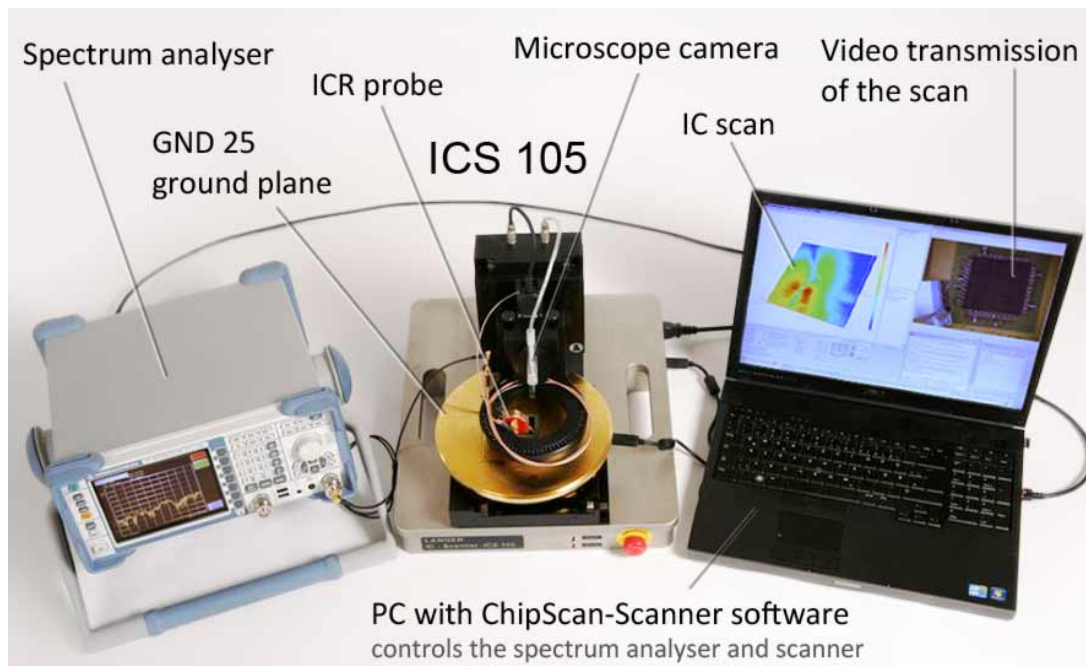
3D scan



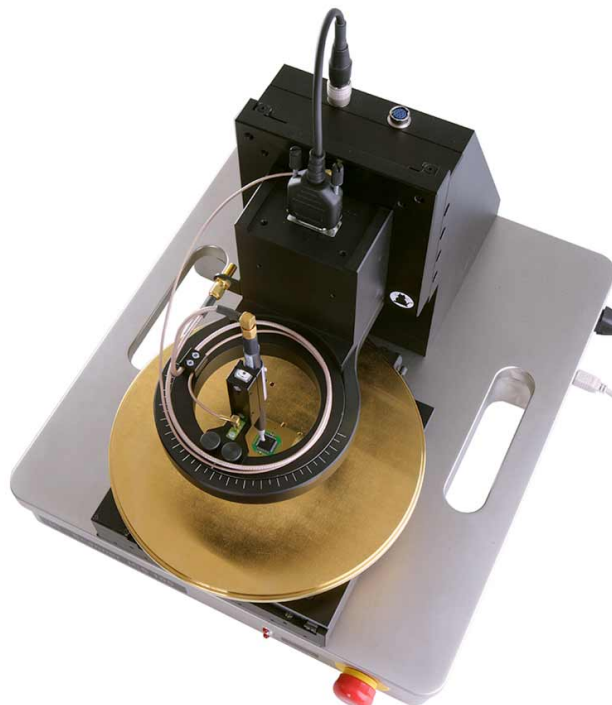
Surface scan



ICS 105 application with CS-Scanner software



ICS 105 with SH 01 probe holder



ICS 105 set

IC Scanner 4-Axis Positioning System

ICS 105 with UH DUT universal holder



ICS 105 set with UH DUT universal holder and device under test

